

Parameter		Symbol	Тур	Max	Units				
Maximum Junction-to-Ambient ^A	t ≤ 10s	$R_{_{ hetaJA}}$	33	40	°C/W				
Maximum Junction-to-Ambient ^A	Steady-State	ιν _θ ja	62	75	°C/W				
Maximum Junction-to-Lead ^C	Steady-State	$R_{\theta JL}$	18	24	°C/W				

Electrical Characteristics (T J=25°C unless otherwise noted)

Symbol	Parameter	Conditions		Min	Тур	Max	Units
STATIC P	ARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =-250μA, V _{GS} =0V		-30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-24V, V _{GS} =0V				-1	μA
			TJ=52°C			-5	
I _{GSS}	Gate-Body leakage current	V _{DS} =0V, V _{GS} =±20V				±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} I _D =-250μA		-1.5	-1.85	-2.5	V
I _{D(ON)}	On state drain current	V _{GS} =-10V, V _{DS} =-5V		-30			Α
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-10V, I _D =-6.5A			38	46	mΩ
			T _J =125°C		53	68	
		V _{GS} =-4.5V, I _D =-5A			58	72	mΩ
g _{FS}	Forward Transconductance	V _{DS} =-5V, I _D =-6.5A			11		S
V _{SD}	Diode Forward Voltage	I _S =-1A,V _{GS} =0V			-0.78	-1	V
ls	Maximum Body-Diode Continuous Current					-3.5	Α
DYNAMIC	PARAMETERS				•		
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-15V, f=1MHz			668	830	pF
C _{oss}	Output Capacitance				126		pF
C _{rss}	Reverse Transfer Capacitance				92		pF
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz			6	9	Ω
SWITCHI	NG PARAMETERS	·					
Q _g (10V)	Total Gate Charge (10V)	V _{GS} =-10V, V _{DS} =-15V, I _D =-6.5A			12.7	16	nC
Q _g (4.5V)	Total Gate Charge (4.5V)				6.4		nC
Q _{gs}	Gate Source Charge				2		nC
Q _{gd}	Gate Drain Charge				4		nC
t _{D(on)}	Turn-On DelayTime	V _{GS} =-10V, V _{DS} =-15V, R _L =2.5Ω, R _{GEN} =3Ω			7.7		ns
t _r	Turn-On Rise Time				6.8		ns
t _{D(off)}	Turn-Off DelayTime				20		ns
t _f	Turn-Off Fall Time				10		ns
t _{rr}	Body Diode Reverse Recovery Time	I _F =-6.5A, dl/dt=100A/μs			22	30	ns
Q _{rr}	Body Diode Reverse Recovery Charge	e I _F =-6.5A, dI/dt=100A/μs			15		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on $1in^2$ FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^{\circ}C$. The value in any a given application depends on the user's specific board design. The current rating is based on the t \leq 10s thermal resistance rating. B: Repetitive rating, pulse width limited by junction temperature.

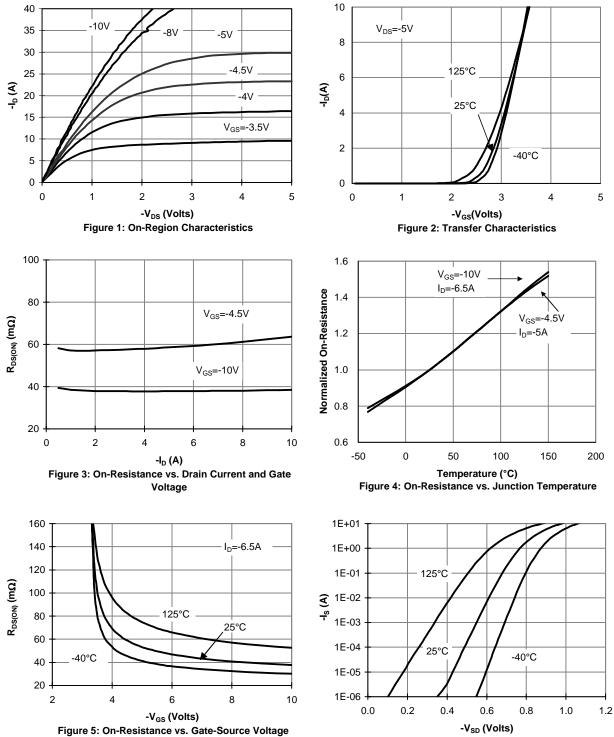
C. The R $_{\rm 0JA}$ is the sum of the thermal impedence from junction to lead R $_{\rm 0JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using < 300 µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25$ °C. The SOA curve provides a single pulse rating.

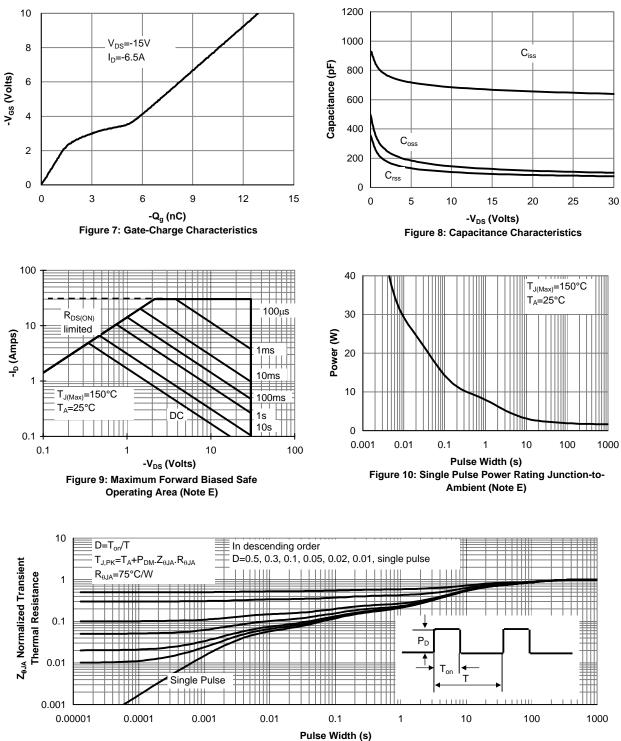
Rev0 Sept 2006

THIS PRODUCT HAS BEEN DESIGNED AND QUALIFIED FOR THE CONSUMER MARKET. APPLICATIONS OR USES AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS ARE NOT AUTHORIZED. AOS DOES NOT ASSUME ANY LIABILITY ARISING OUT OF SUCH APPLICATIONS OR USES OF ITS PRODUCTS. AOS RESERVES THE RIGHT TO IMPROVE PRODUCT DESIGN, FUNCTIONS AND RELIABILITY WITHOUT NOTICE.



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 6: Body-Diode Characteristics



TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

Figure 11: Normalized Maximum Transient Thermal Impedance(Note E)